

Notice of References Cited	Application/Control No. 10/716,436	Applicant(s)/Patent Under Reexamination LEE, PHAL JIN	
	Examiner Joseph L. Perrin, PhD	Art Unit 1746	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,640,637	11-2003	Baek, Seung Taek	73/652
*	B	US-6,336,348	01-2002	Lee et al.	68/12.27
*	C	US-6,292,966	09-2001	Lim et al.	8/158
*	D	US-5,850,746	12-1998	Lee, Dong Geun	68/12.06
*	E	US-5,315,847	05-1994	Takeda et al.	68/12.02
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 03077584 A	04-1991	Japan	TOKUCHI et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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